



Test Report

No. :KA/2007/81383 Date: 2007/08/30 Page: 1 of 3

RALEC ELECTRONIC CORPORATION
NO.1, CENTRAL 2nd STREET, NANTZE EXPORT PROCESSING ZONE, KAOHSIUNG
,TAIWAN.



The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description	: LEAD FREE CHIP RESISTOR ARRAY PRODUCT
Style/Item No.	: RTA03-2D(0603-8P4R)
Color	: SILVER/BLACK
Sample Receiving Date	: 2007/08/23
Testing Period	: 2007/08/23 TO 2007/8/30

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Test Requested	: In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.
Test Method	: (1) With reference to US EPA Method 3050B for Lead Content. Analysis was performed by ICP-AES.
Test Result(s)	: Please refer to next page(s).


Katherine Ho / Supervisor
 Signed for and on behalf of
 SGS Taiwan Limited

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